

Current Coperations

Collaborators	Topic	Institution
Prof. Lionel Kimerling	Self-Assembling SiGe and Si/SOI quantum dots	Dept. of Materials Science and Eng., Massachusetts Institute of Technology
Prof. Jerry L. Whitten	Quantum Chemistry Calculations	Dept. Of Chemistry, North Carolina State University
Prof. Eicke R. Weber	Micro FTIR using Synchrotron Light Source	University of California, Dept. of Materials Science and Engineering, Berkeley CA, USA
Dr Michael Martin	Synchrotron High Resolution Fourier Transform IR spectroscopy	Lawrence Berkely National Lab Advanced Light Source, Beam line 4
Dr Nobumichi Tamura	Synchrotron x-ray microprobe imaging of defects	Lawrence Berkely National Lab Advanced Light Source
Prof. Deren Yang	Specialty crystal growth: Nitrogen doped CZ silicon	State Key Lab of Silicon Materials at Zhejiang University, China
Prof. Nouashi Inoue	Simulation of IR absorption spectroscopy (FTIR)	Osaka University, Japon
Dr Mark Johnson	Cathodoluminescence of strained silicon on SiGe Cathodoluminescence of strained and nano-indented N-CZ Si	Dept. of Materials Science and Engineering North Carolina State University
Dr. Gerd Dusher	High Resolution TEM Z-contrast, EELS	Oak Ridge National Laboratories, TN
Prof. A. La Rosa	Near Field Scanning Microscopy	Department of Physics, Portland State University, Portland, Oregon
Prof. H. Hallen		Dept. of Physics, North Carolina State University
Dr. Scott Lassel	Neutron Irradiation of silicon wafers	Dept. of Nuclear Engineering North Carolina State University
Dr. Ted Cizek	Specialty crystal growth: Nitrogen doped float zone silicon	National Renewable Energy Laboratory, Golden, CO.
Dr. Masataka Hourai	Specialty crystal growth: Nitrogen doped CZ silicon	Research and Development Center Sumitomo Metal Industries, Ltd. , Sitix Division, Saga, Japon
Prof. Kuji Sueoka	Modeling of extended defects in silicon	
Dr. Shigeru Umeno	Defect profiling using OPP	

Past Cooperations

Collaborator	Topic	Institution
Dr. Dieter Griffis	High resolution SIMS imaging	Analytical Instrumentation Facility North Carolina State University
Prof. Kasichainula Jagannadham	Thin film electrical characterization	Dept. of Materials Science and Eng., North Carolina State University
Dr. Jean F. Daviet	Rapid Thermal Processing	Mattson Technology, Inc. Fremont CA
Dr. Fernando Gonzalez	<ul style="list-style-type: none"> • Drift induced Impurity Gettering in silicon (DIG). • MeV gettering with ion implantation • Lifetime and SPV measurement, 	Micron Technology Inc., Boise, Idaho
Prof. Ghanem Marrakchi	Defect Spectroscopy, Photo Induced Current Transient Spectroscopy	Laboratoire de Physique de la Matière INSA, Lyon, France.
Prof. Raouf Bennaceur	First Principles Calculations for III-V surface reconstruction.	Faculté des Sciences de Tunis, Tunisie.